

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BEM ET AL.	
		Examiner Jacques Veillard	Art Unit 2165	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0088308	05-2004	Bailey et al.	707/100
*	B	US-2002/0083067	06-2002	Tamayo et al.	707/100
*	C	US-2002/0184181	12-2002	Agarwal et al.	707/1
*	D	US-6,523,020	02-2003	Weiss, Sholom	706/47
*	E	US-7,065,524	06-2006	Lee, Edmund G.	707/6
*	F	US-6,311,175	10-2001	Adriaans et al.	706/25
*	G	US-5,897,627	04-1999	Leivian et al.	706/12
H	US-				
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Weis et al.: Rule-based Machine Learning Methods for Functional Prediction, Journal of AI Research, vol.3, Dec. 1995, pages 383-403.
	V	J. Friedman et al.: Additive Logistic Regression: A Statistical View of Boosting, Technical Report, Stanford University Statistics Department, Jul. 1998, pages 1-45.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.